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AMD Xilinx - XC4003E-2VQ100C Datasheet



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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	100
Number of Logic Elements/Cells	238
Total RAM Bits	3200
Number of I/O	77
Number of Gates	3000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc4003e-2vq100c

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

		Max Logic	Max. RAM	Typical			Number	
	Logic	Gates	Bits	Gate Range	CLB	Total	of	Max.
Device	Cells	(No RAM)	(No Logic)	(Logic and RAM)*	Matrix	CLBs	Flip-Flops	User I/O
XC4002XL	152	1,600	2,048	1,000 - 3,000	8 x 8	64	256	64
XC4003E	238	3,000	3,200	2,000 - 5,000	10 x 10	100	360	80
XC4005E/XL	466	5,000	6,272	3,000 - 9,000	14 x 14	196	616	112
XC4006E	608	6,000	8,192	4,000 - 12,000	16 x 16	256	768	128
XC4008E	770	8,000	10,368	6,000 - 15,000	18 x 18	324	936	144
XC4010E/XL	950	10,000	12,800	7,000 - 20,000	20 x 20	400	1,120	160
XC4013E/XL	1368	13,000	18,432	10,000 - 30,000	24 x 24	576	1,536	192
XC4020E/XL	1862	20,000	25,088	13,000 - 40,000	28 x 28	784	2,016	224
XC4025E	2432	25,000	32,768	15,000 - 45,000	32 x 32	1,024	2,560	256
XC4028EX/XL	2432	28,000	32,768	18,000 - 50,000	32 x 32	1,024	2,560	256
XC4036EX/XL	3078	36,000	41,472	22,000 - 65,000	36 x 36	1,296	3,168	288
XC4044XL	3800	44,000	51,200	27,000 - 80,000	40 x 40	1,600	3,840	320
XC4052XL	4598	52,000	61,952	33,000 - 100,000	44 x 44	1,936	4,576	352
XC4062XL	5472	62,000	73,728	40,000 - 130,000	48 x 48	2,304	5,376	384
XC4085XL	7448	85,000	100,352	55,000 - 180,000	56 x 56	3,136	7,168	448

Table 1: XC4000E and XC4000X Series Field Programmable Gate Arrays

* Max values of Typical Gate Range include 20-30% of CLBs used as RAM.

Note: All functionality in low-voltage families is the same as in the corresponding 5-Volt family, except where numerical references are made to timing or power.

Description

XC4000 Series devices are implemented with a regular, flexible, programmable architecture of Configurable Logic Blocks (CLBs), interconnected by a powerful hierarchy of versatile routing resources, and surrounded by a perimeter of programmable Input/Output Blocks (IOBs). They have generous routing resources to accommodate the most complex interconnect patterns.

The devices are customized by loading configuration data into internal memory cells. The FPGA can either actively read its configuration data from an external serial or byte-parallel PROM (master modes), or the configuration data can be written into the FPGA from an external device (slave and peripheral modes).

XC4000 Series FPGAs are supported by powerful and sophisticated software, covering every aspect of design from schematic or behavioral entry, floor planning, simulation, automatic block placement and routing of interconnects, to the creation, downloading, and readback of the configuration bit stream.

Because Xilinx FPGAs can be reprogrammed an unlimited number of times, they can be used in innovative designs

where hardware is changed dynamically, or where hardware must be adapted to different user applications. FPGAs are ideal for shortening design and development cycles, and also offer a cost-effective solution for production rates well beyond 5,000 systems per month.

Taking Advantage of Re-configuration

FPGA devices can be re-configured to change logic function while resident in the system. This capability gives the system designer a new degree of freedom not available with any other type of logic.

Hardware can be changed as easily as software. Design updates or modifications are easy, and can be made to products already in the field. An FPGA can even be re-configured dynamically to perform different functions at different times.

Re-configurable logic can be used to implement system self-diagnostics, create systems capable of being re-configured for different environments or operations, or implement multi-purpose hardware for a given application. As an added benefit, using re-configurable FPGA devices simplifies hardware design and debugging and shortens product time-to-market.

Detailed Functional Description

XC4000 Series devices achieve high speed through advanced semiconductor technology and improved architecture. The XC4000E and XC4000X support system clock rates of up to 80 MHz and internal performance in excess of 150 MHz. Compared to older Xilinx FPGA families, XC4000 Series devices are more powerful. They offer on-chip edge-triggered and dual-port RAM, clock enables on I/O flip-flops, and wide-input decoders. They are more versatile in many applications, especially those involving RAM. Design cycles are faster due to a combination of increased routing resources and more sophisticated software.

Basic Building Blocks

Xilinx user-programmable gate arrays include two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing the user's logic.
- IOBs provide the interface between the package pins and internal signal lines.

Three other types of circuits are also available:

- 3-State buffers (TBUFs) driving horizontal longlines are associated with each CLB.
- Wide edge decoders are available around the periphery of each device.
- An on-chip oscillator is provided.

Programmable interconnect resources provide routing paths to connect the inputs and outputs of these configurable elements to the appropriate networks.

The functionality of each circuit block is customized during configuration by programming internal static memory cells. The values stored in these memory cells determine the logic functions and interconnections implemented in the FPGA. Each of these available circuits is described in this section.

Configurable Logic Blocks (CLBs)

Configurable Logic Blocks implement most of the logic in an FPGA. The principal CLB elements are shown in Figure 1. Two 4-input function generators (F and G) offer unrestricted versatility. Most combinatorial logic functions need four or fewer inputs. However, a third function generator (H) is provided. The H function generator has three inputs. Either zero, one, or two of these inputs can be the outputs of F and G; the other input(s) are from outside the CLB. The CLB can, therefore, implement certain functions of up to nine variables, like parity check or expandable-identity comparison of two sets of four inputs. Each CLB contains two storage elements that can be used to store the function generator outputs. However, the storage elements and function generators can also be used independently. These storage elements can be configured as flip-flops in both XC4000E and XC4000X devices; in the XC4000X they can optionally be configured as latches. DIN can be used as a direct input to either of the two storage elements. H1 can drive the other through the H function generator. Function generator outputs can also drive two outputs independent of the storage element outputs. This versatility increases logic capacity and simplifies routing.

Thirteen CLB inputs and four CLB outputs provide access to the function generators and storage elements. These inputs and outputs connect to the programmable interconnect resources outside the block.

Function Generators

Four independent inputs are provided to each of two function generators (F1 - F4 and G1 - G4). These function generators, with outputs labeled F' and G', are each capable of implementing any arbitrarily defined Boolean function of four inputs. The function generators are implemented as memory look-up tables. The propagation delay is therefore independent of the function implemented.

A third function generator, labeled H', can implement any Boolean function of its three inputs. Two of these inputs can optionally be the F' and G' functional generator outputs. Alternatively, one or both of these inputs can come from outside the CLB (H2, H0). The third input must come from outside the block (H1).

Signals from the function generators can exit the CLB on two outputs. F' or H' can be connected to the X output. G' or H' can be connected to the Y output.

A CLB can be used to implement any of the following functions:

- any function of up to four variables, plus any second function of up to four unrelated variables, plus any third function of up to three unrelated variables¹
- any single function of five variables
- any function of four variables together with some functions of six variables
- some functions of up to nine variables.

Implementing wide functions in a single block reduces both the number of blocks required and the delay in the signal path, achieving both increased capacity and speed.

The versatility of the CLB function generators significantly improves system speed. In addition, the design-software tools can deal with each function generator independently. This flexibility improves cell usage.

^{1.} When three separate functions are generated, one of the function outputs must be captured in a flip-flop internal to the CLB. Only two unregistered function generator outputs are available from the CLB.

tions of the CLB, with the exception of the redefinition of the control signals. In 16x2 and 16x1 modes, the H' function generator can be used to implement Boolean functions of F', G', and D1, and the D flip-flops can latch the F', G', H', or D0 signals.

Single-Port Edge-Triggered Mode

Edge-triggered (synchronous) RAM simplifies timing requirements. XC4000 Series edge-triggered RAM timing operates like writing to a data register. Data and address are presented. The register is enabled for writing by a logic High on the write enable input, WE. Then a rising or falling clock edge loads the data into the register, as shown in Figure 3.



Figure 3: Edge-Triggered RAM Write Timing

Complex timing relationships between address, data, and write enable signals are not required, and the external write enable pulse becomes a simple clock enable. The active edge of WCLK latches the address, input data, and WE signals. An internal write pulse is generated that performs the write. See Figure 4 and Figure 5 for block diagrams of a CLB configured as 16x2 and 32x1 edge-triggered, single-port RAM.

The relationships between CLB pins and RAM inputs and outputs for single-port, edge-triggered mode are shown in Table 5.

The Write Clock input (WCLK) can be configured as active on either the rising edge (default) or the falling edge. It uses the same CLB pin (K) used to clock the CLB flip-flops, but it can be independently inverted. Consequently, the RAM output can optionally be registered within the same CLB either by the same clock edge as the RAM, or by the opposite edge of this clock. The sense of WCLK applies to both function generators in the CLB when both are configured as RAM.

The WE pin is active-High and is not invertible within the CLB.

Note: The pulse following the active edge of WCLK (T_{WPS} in Figure 3) must be less than one millisecond wide. For most applications, this requirement is not overly restrictive; however, it must not be forgotten. Stopping WCLK at this point in the write cycle could result in excessive current and even damage to the larger devices if many CLBs are configured as edge-triggered RAM.

Table 5: Single-Port Edge-Triggered RAM Signals

RAM Signal	CLB Pin	Function
D	D0 or D1 (16x2, 16x1), D0 (32x1)	Data In
A[3:0]	F1-F4 or G1-G4	Address
A[4]	D1 (32x1)	Address
WE	WE	Write Enable
WCLK	К	Clock
SPO (Data Out)	F' or G'	Single Port Out (Data Out)

Dual-Port Edge-Triggered Mode

In dual-port mode, both the F and G function generators are used to create a single 16x1 RAM array with one write port and two read ports. The resulting RAM array can be read and written simultaneously at two independent addresses. Simultaneous read and write operations at the same address are also supported.

Dual-port mode always has edge-triggered write timing, as shown in Figure 3.

Figure 6 shows a simple model of an XC4000 Series CLB configured as dual-port RAM. One address port, labeled A[3:0], supplies both the read and write address for the F function generator. This function generator behaves the same as a 16x1 single-port edge-triggered RAM array. The RAM output, Single Port Out (SPO), appears at the F function generator output. SPO, therefore, reflects the data at address A[3:0].

The other address port, labeled DPRA[3:0] for Dual Port Read Address, supplies the read address for the G function generator. The write address for the G function generator, however, comes from the address A[3:0]. The output from this 16x1 RAM array, Dual Port Out (DPO), appears at the G function generator output. DPO, therefore, reflects the data at address DPRA[3:0].

Therefore, by using A[3:0] for the write address and DPRA[3:0] for the read address, and reading only the DPO output, a FIFO that can read and write simultaneously is easily generated. Simultaneous access doubles the effective throughput of the FIFO.

The relationships between CLB pins and RAM inputs and outputs for dual-port, edge-triggered mode are shown in Table 6. See Figure 7 on page 16 for a block diagram of a CLB configured in this mode.





Table 6: Dual-Port Edge-Triggered RAM Signals

RAM Signal	CLB Pin	Function
D	D0	Data In
A[3:0]	F1-F4	Read Address for F,
		Write Address for F and G
DPRA[3:0]	G1-G4	Read Address for G
WE	WE	Write Enable
WCLK	K	Clock
SPO	F'	Single Port Out
		(addressed by A[3:0])
DPO	G'	Dual Port Out
		(addressed by DPRA[3:0])

Note: The pulse following the active edge of WCLK (T_{WPS} in Figure 3) must be less than one millisecond wide. For most applications, this requirement is not overly restrictive; however, it must not be forgotten. Stopping WCLK at this point in the write cycle could result in excessive current and even damage to the larger devices if many CLBs are configured as edge-triggered RAM.

Single-Port Level-Sensitive Timing Mode

Note: Edge-triggered mode is recommended for all new designs. Level-sensitive mode, also called asynchronous mode, is still supported for XC4000 Series backward-compatibility with the XC4000 family.

Level-sensitive RAM timing is simple in concept but can be complicated in execution. Data and address signals are presented, then a positive pulse on the write enable pin (WE) performs a write into the RAM at the designated address. As indicated by the "level-sensitive" label, this RAM acts like a latch. During the WE High pulse, changing the data lines results in new data written to the old address. Changing the address lines while WE is High results in spurious data written to the new address—and possibly at other addresses as well, as the address lines inevitably do not all change simultaneously.

The user must generate a carefully timed WE signal. The delay on the WE signal and the address lines must be carefully verified to ensure that WE does not become active until after the address lines have settled, and that WE goes inactive before the address lines change again. The data must be stable before and after the falling edge of WE.

In practical terms, WE is usually generated by a 2X clock. If a 2X clock is not available, the falling edge of the system clock can be used. However, there are inherent risks in this approach, since the WE pulse must be guaranteed inactive before the next rising edge of the system clock. Several older application notes are available from Xilinx that discuss the design of level-sensitive RAMs.

However, the edge-triggered RAM available in the XC4000 Series is superior to level-sensitive RAM for almost every application.



Figure 14: Detail of XC4000E Dedicated Carry Logic

Input/Output Blocks (IOBs)

User-configurable input/output blocks (IOBs) provide the interface between external package pins and the internal logic. Each IOB controls one package pin and can be configured for input, output, or bidirectional signals.

Figure 15 shows a simplified block diagram of the XC4000E IOB. A more complete diagram which includes the boundary scan logic of the XC4000E IOB can be found in Figure 40 on page 43, in the "Boundary Scan" section.

The XC4000X IOB contains some special features not included in the XC4000E IOB. These features are high-lighted in a simplified block diagram found in Figure 16, and discussed throughout this section. When XC4000X special features are discussed, they are clearly identified in the text. Any feature not so identified is present in both XC4000E and XC4000X devices.

IOB Input Signals

Two paths, labeled I1 and I2 in Figure 15 and Figure 16, bring input signals into the array. Inputs also connect to an input register that can be programmed as either an edge-triggered flip-flop or a level-sensitive latch.

The choice is made by placing the appropriate library symbol. For example, IFD is the basic input flip-flop (rising edge triggered), and ILD is the basic input latch (transparent-High). Variations with inverted clocks are available, and some combinations of latches and flip-flops can be implemented in a single IOB, as described in the *XACT Libraries Guide*.

The XC4000E inputs can be globally configured for either TTL (1.2V) or 5.0 volt CMOS thresholds, using an option in the bitstream generation software. There is a slight input hysteresis of about 300mV. The XC4000E output levels are also configurable; the two global adjustments of input threshold and output level are independent.

Inputs on the XC4000XL are TTL compatible and 3.3V CMOS compatible. Outputs on the XC4000XL are pulled to the 3.3V positive supply.

The inputs of XC4000 Series 5-Volt devices can be driven by the outputs of any 3.3-Volt device, if the 5-Volt inputs are in TTL mode.

Supported sources for XC4000 Series device inputs are shown in Table 8.



Figure 15: Simplified Block Diagram of XC4000E IOB







 Table 8: Supported Sources for XC4000 Series Device

 Inputs

	XC400 Series	0E/EX Inputs	XC4000XL Series Inputs	
Source	5 V, TTL	5 V, CMOS	3.3 V CMOS	
Any device, Vcc = 3.3 V, CMOS outputs	\checkmark	Unroli		
XC4000 Series, Vcc = 5 V, TTL outputs	V	-able		
Any device, $Vcc = 5 V$, TTL outputs (Voh $\leq 3.7 V$)	V	Data		
Any device, Vcc = 5 V, CMOS outputs	V	V	\checkmark	

XC4000XL 5-Volt Tolerant I/Os

The I/Os on the XC4000XL are fully 5-volt tolerant even though the V_{CC} is 3.3 volts. This allows 5 V signals to directly connect to the XC4000XL inputs without damage, as shown in Table 8. In addition, the 3.3 volt V_{CC} can be applied before or after 5 volt signals are applied to the I/Os. This makes the XC4000XL immune to power supply sequencing problems.

Registered Inputs

The I1 and I2 signals that exit the block can each carry either the direct or registered input signal.

The input and output storage elements in each IOB have a common clock enable input, which, through configuration, can be activated individually for the input or output flip-flop, or both. This clock enable operates exactly like the EC pin on the XC4000 Series CLB. It cannot be inverted within the IOB.

The storage element behavior is shown in Table 9.

Table 9: Input Register Functionality(active rising edge is shown)

Mode	Clock	Clock Enable	D	Q
Power-Up or GSR	Х	Х	Х	SR
Flip-Flop		1*	D	D
	0	X	Х	Q
Latch	1	1*	Х	Q
	0	1*	D	D
Both	Х	0	Х	Q

Legend:

Х

_ Don't care

Rising edge

SR Set or Reset value. Reset is default.

0* Input is Low or unconnected (default value)

1* Input is High or unconnected (default value)

Optional Delay Guarantees Zero Hold Time

The data input to the register can optionally be delayed by several nanoseconds. With the delay enabled, the setup time of the input flip-flop is increased so that normal clock routing does not result in a positive hold-time requirement. A positive hold time requirement can lead to unreliable, temperature- or processing-dependent operation.

The input flip-flop setup time is defined between the data measured at the device I/O pin and the clock input at the IOB (not at the clock pin). Any routing delay from the device clock pin to the clock input of the IOB must, therefore, be subtracted from this setup time to arrive at the real setup time requirement relative to the device pins. A short specified setup time might, therefore, result in a negative setup time at the device pins, i.e., a positive hold-time requirement.

When a delay is inserted on the data line, more clock delay can be tolerated without causing a positive hold-time requirement. Sufficient delay eliminates the possibility of a data hold-time requirement at the external pin. The maximum delay is therefore inserted as the default.

The XC4000E IOB has a one-tap delay element: either the delay is inserted (default), or it is not. The delay guarantees a zero hold time with respect to clocks routed through any of the XC4000E global clock buffers. (See "Global Nets and Buffers (XC4000E only)" on page 35 for a description of the global clock buffers in the XC4000E.) For a shorter input register setup time, with non-zero hold, attach a NODELAY attribute or property to the flip-flop.

The XC4000X IOB has a two-tap delay element, with choices of a full delay, a partial delay, or no delay. The attributes or properties used to select the desired delay are shown in Table 10. The choices are no added attribute, MEDDELAY, and NODELAY. The default setting, with no added attribute, ensures no hold time with respect to any of the XC4000X clock buffers, including the Global Low-Skew buffers. MEDDELAY ensures no hold time with respect to the Global Early buffers. Inputs with NODELAY may have a positive hold time with respect to all clock buffers. For a description of each of these buffers, see "Global Nets and Buffers (XC4000X only)" on page 37.

Table	10:	XC4000X	IOB	Input	Delay	Element
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Г	
Value	When to Use
full delay	Zero Hold with respect to Global
(default, no	Low-Skew Buffer, Global Early Buffer
attribute added)	
MEDDELAY	Zero Hold with respect to Global Early
	Buffer
NODELAY	Short Setup, positive Hold time

Output Multiplexer/2-Input Function Generator (XC4000X only)

As shown in Figure 16 on page 21, the output path in the XC4000X IOB contains an additional multiplexer not available in the XC4000E IOB. The multiplexer can also be configured as a 2-input function generator, implementing a pass-gate, AND-gate, OR-gate, or XOR-gate, with 0, 1, or 2 inverted inputs. The logic used to implement these functions is shown in the upper gray area of Figure 16.

When configured as a multiplexer, this feature allows two output signals to time-share the same output pad; effectively doubling the number of device outputs without requiring a larger, more expensive package.

When the MUX is configured as a 2-input function generator, logic can be implemented within the IOB itself. Combined with a Global Early buffer, this arrangement allows very high-speed gating of a single signal. For example, a wide decoder can be implemented in CLBs, and its output gated with a Read or Write Strobe Driven by a BUFGE buffer, as shown in Figure 19. The critical-path pin-to-pin delay of this circuit is less than 6 nanoseconds.

As shown in Figure 16, the IOB input pins Out, Output Clock, and Clock Enable have different delays and different flexibilities regarding polarity. Additionally, Output Clock sources are more limited than the other inputs. Therefore, the Xilinx software does not move logic into the IOB function generators unless explicitly directed to do so.

The user can specify that the IOB function generator be used, by placing special library symbols beginning with the letter "O." For example, a 2-input AND-gate in the IOB function generator is called OAND2. Use the symbol input pin labelled "F" for the signal on the critical path. This signal is placed on the OK pin — the IOB input with the shortest delay to the function generator. Two examples are shown in Figure 20.



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Other IOB Options

There are a number of other programmable options in the XC4000 Series IOB.

Pull-up and Pull-down Resistors

Programmable pull-up and pull-down resistors are useful for tying unused pins to Vcc or Ground to minimize power consumption and reduce noise sensitivity. The configurable pull-up resistor is a p-channel transistor that pulls to Vcc. The configurable pull-down resistor is an n-channel transistor that pulls to Ground.

The value of these resistors is 50 k Ω – 100 k Ω . This high value makes them unsuitable as wired-AND pull-up resistors.

The pull-up resistors for most user-programmable IOBs are active during the configuration process. See Table 22 on page 58 for a list of pins with pull-ups active before and during configuration.

After configuration, voltage levels of unused pads, bonded or un-bonded, must be valid logic levels, to reduce noise sensitivity and avoid excess current. Therefore, by default, unused pads are configured with the internal pull-up resistor active. Alternatively, they can be individually configured with the pull-down resistor, or as a driven output, or to be driven by an external source. To activate the internal pull-up, attach the PULLUP library component to the net attached to the pad. To activate the internal pull-down, attach the PULLDOWN library component to the net attached to the pad.

Independent Clocks

Separate clock signals are provided for the input and output flip-flops. The clock can be independently inverted for each flip-flop within the IOB, generating either falling-edge or rising-edge triggered flip-flops. The clock inputs for each IOB are independent, except that in the XC4000X, the Fast Capture latch shares an IOB input with the output clock pin.

Early Clock for IOBs (XC4000X only)

Special early clocks are available for IOBs. These clocks are sourced by the same sources as the Global Low-Skew buffers, but are separately buffered. They have fewer loads and therefore less delay. The early clock can drive either the IOB output clock or the IOB input clock, or both. The early clock allows fast capture of input data, and fast clock-to-output on output data. The Global Early buffers that drive these clocks are described in "Global Nets and Buffers (XC4000X only)" on page 37.

Global Set/Reset

As with the CLB registers, the Global Set/Reset signal (GSR) can be used to set or clear the input and output registers, depending on the value of the INIT attribute or property. The two flip-flops can be individually configured to set 6

or clear on reset and after configuration. Other than the global GSR net, no user-controlled set/reset signal is available to the I/O flip-flops. The choice of set or clear applies to both the initial state of the flip-flop and the response to the Global Set/Reset pulse. See "Global Set/Reset" on page 11 for a description of how to use GSR.

JTAG Support

Embedded logic attached to the IOBs contains test structures compatible with IEEE Standard 1149.1 for boundary scan testing, permitting easy chip and board-level testing. More information is provided in "Boundary Scan" on page 42.

Three-State Buffers

A pair of 3-state buffers is associated with each CLB in the array. (See Figure 27 on page 30.) These 3-state buffers can be used to drive signals onto the nearest horizontal longlines above and below the CLB. They can therefore be used to implement multiplexed or bidirectional buses on the horizontal longlines, saving logic resources. Programmable pull-up resistors attached to these longlines help to implement a wide wired-AND function.

The buffer enable is an active-High 3-state (i.e. an active-Low enable), as shown in Table 13.

Another 3-state buffer with similar access is located near each I/O block along the right and left edges of the array. (See Figure 33 on page 34.)

The horizontal longlines driven by the 3-state buffers have a weak keeper at each end. This circuit prevents undefined floating levels. However, it is overridden by any driver, even a pull-up resistor.

Special longlines running along the perimeter of the array can be used to wire-AND signals coming from nearby IOBs or from internal longlines. These longlines form the wide edge decoders discussed in "Wide Edge Decoders" on page 27.

Three-State Buffer Modes

The 3-state buffers can be configured in three modes:

- Standard 3-state buffer
- Wired-AND with input on the I pin
- Wired OR-AND

Standard 3-State Buffer

All three pins are used. Place the library element BUFT. Connect the input to the I pin and the output to the O pin. The T pin is an active-High 3-state (i.e. an active-Low enable). Tie the T pin to Ground to implement a standard buffer.

Wired-AND with Input on the I Pin

The buffer can be used as a Wired-AND. Use the WAND1 library symbol, which is essentially an open-drain buffer. WAND4, WAND8, and WAND16 are also available. See the *XACT Libraries Guide* for further information.

The T pin is internally tied to the I pin. Connect the input to the I pin and the output to the O pin. Connect the outputs of all the WAND1s together and attach a PULLUP symbol.

Wired OR-AND

The buffer can be configured as a Wired OR-AND. A High level on either input turns off the output. Use the WOR2AND library symbol, which is essentially an open-drain 2-input OR gate. The two input pins are functionally equivalent. Attach the two inputs to the I0 and I1 pins and tie the output to the O pin. Tie the outputs of all the WOR2ANDs together and attach a PULLUP symbol.

Three-State Buffer Examples

Figure 21 shows how to use the 3-state buffers to implement a wired-AND function. When all the buffer inputs are High, the pull-up resistor(s) provide the High output.

Figure 22 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

Pay particular attention to the polarity of the T pin when using these buffers in a design. Active-High 3-state (T) is identical to an active-Low output enable, as shown in Table 13.

Table 13: Three-State Buffer Functionality

IN	Т	OUT
Х	1	Z
IN	0	IN



Figure 21: Open-Drain Buffers Implement a Wired-AND Function

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XC4000X only



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Figure 36: Any BUFGLS (GCK1 - GCK8) Can Drive Any or All Clock Inputs on the Device

Global Early Buffers

Each corner of the XC4000X device has two Global Early buffers. The primary purpose of the Global Early buffers is to provide an earlier clock access than the potentially heavily-loaded Global Low-Skew buffers. A clock source applied to both buffers will result in the Global Early clock edge occurring several nanoseconds earlier than the Global Low-Skew buffer clock edge, due to the lighter loading.

Global Early buffers also facilitate the fast capture of device inputs, using the Fast Capture latches described in "IOB Input Signals" on page 20. For Fast Capture, take a single clock signal, and route it through both a Global Early buffer and a Global Low-Skew buffer. (The two buffers share an input pad.) Use the Global Early buffer to clock the Fast Capture latch, and the Global Low-Skew buffer to clock the normal input flip-flop or latch, as shown in Figure 17 on page 23.

The Global Early buffers can also be used to provide a fast Clock-to-Out on device output pins. However, an early clock in the output flip-flop IOB must be taken into consideration when calculating the internal clock speed for the design.

The Global Early buffers at the left and right edges of the chip have slightly different capabilities than the ones at the top and bottom. Refer to Figure 37, Figure 38, and Figure 35 on page 36 while reading the following explanation.

Each Global Early buffer can access the eight vertical Global lines for all CLBs in the quadrant. Therefore, only one-fourth of the CLB clock pins can be accessed. This restriction is in large part responsible for the faster speed of the buffers, relative to the Global Low-Skew buffers.



Figure 37: Left and Right BUFGEs Can Drive Any or All Clock Inputs in Same Quadrant or Edge (GCK1 is shown. GCK2, GCK5 and GCK6 are similar.)

The left-side Global Early buffers can each drive two of the four vertical lines accessing the IOBs on the entire left edge of the device. The right-side Global Early buffers can each drive two of the eight vertical lines accessing the IOBs on the entire right edge of the device. (See Figure 37.)

Each left and right Global Early buffer can also drive half of the IOBs along either the top or bottom edge of the device, using a dedicated line that can only be accessed through the Global Early buffers.

The top and bottom Global Early buffers can drive half of the IOBs along either the left or right edge of the device, as shown in Figure 38. They can only access the top and bottom IOBs via the CLB global lines.



Figure 38: Top and Bottom BUFGEs Can Drive Any or All Clock Inputs in Same Quadrant (GCK8 is shown. GCK3, GCK4 and GCK7 are similar.)

The top and bottom Global Early buffers are about 1 ns slower clock to out than the left and right Global Early buffers.

The Global Early buffers can be driven by either semi-dedicated pads or internal logic. They share pads with the Global Low-Skew buffers, so a single net can drive both global buffers, as described above.

To use a Global Early buffer, place a BUFGE element in a schematic or in HDL code. If desired, attach a LOC attribute or property to direct placement to the designated location. For example, attach a LOC=T attribute or property to direct that a BUFGE be placed in one of the two Global Early buffers on the top edge of the device, or a LOC=TR to indicate the Global Early buffer on the top edge of the device, on the right.

Power Distribution

Power for the FPGA is distributed through a grid to achieve high noise immunity and isolation between logic and I/O. Inside the FPGA, a dedicated Vcc and Ground ring surrounding the logic array provides power to the I/O drivers, as shown in Figure 39. An independent matrix of Vcc and Ground lines supplies the interior logic of the device.

This power distribution grid provides a stable supply and ground for all internal logic, providing the external package power pins are all connected and appropriately de-coupled. Typically, a 0.1 μ F capacitor connected between each Vcc pin and the board's Ground plane will provide adequate de-coupling.

Output buffers capable of driving/sinking the specified 12 mA loads under specified worst-case conditions may be capable of driving/sinking up to 10 times as much current under best case conditions.

Noise can be reduced by minimizing external load capacitance and reducing simultaneous output transitions in the same direction. It may also be beneficial to locate heavily loaded output buffers near the Ground pads. The I/O Block output buffers have a slew-rate limited mode (default) which should be used where output rise and fall times are not speed-critical.



Figure 39: XC4000 Series Power Distribution

Pin Descriptions

There are three types of pins in the XC4000 Series devices:

- Permanently dedicated pins
- User I/O pins that can have special functions
- Unrestricted user-programmable I/O pins.

Before and during configuration, all outputs not used for the configuration process are 3-stated with a 50 k Ω - 100 k Ω pull-up resistor.

After configuration, if an IOB is unused it is configured as an input with a 50 k Ω - 100 k Ω pull-up resistor.

XC4000 Series devices have no dedicated Reset input. Any user I/O can be configured to drive the Global Set/Reset net, GSR. See "Global Set/Reset" on page 11 for more information on GSR.

XC4000 Series devices have no Powerdown control input, as the XC3000 and XC2000 families do. The XC3000/XC2000 Powerdown control also 3-stated all of the device

I/O pins. For XC4000 Series devices, use the global 3-state net, GTS, instead. This net 3-states all outputs, but does not place the device in low-power mode. See "IOB Output Signals" on page 23 for more information on GTS.

Device pins for XC4000 Series devices are described in Table 16. Pin functions during configuration for each of the seven configuration modes are summarized in Table 22 on page 58, in the "Configuration Timing" section.



Table 16: Pin Descriptions (Continued)

	I/O	I/O			
	During	After			
Pin Name	Config.	Config.	Pin Description		
<u>CS0,</u> CS1, WS, RS	I	I/O	These four inputs are used in Asynchronous Peripheral mode. The chip is selected when $\overline{\text{CS0}}$ is Low and CS1 is High. While the chip is selected, a Low on Write Strobe $(\overline{\text{WS}})$ loads the data present on the D0 - D7 inputs into the internal data buffer. A Low on Read Strobe ($\overline{\text{RS}}$) changes D7 into a status output — High if Ready, Low if Busy — and drives D0 - D6 High. In Express mode, CS1 is used as a serial-enable signal for daisy-chaining. $\overline{\text{WS}}$ and $\overline{\text{RS}}$ should be mutually exclusive, but if both are Low simultaneously, the Write Strobe overrides. After configuration, these are user-programmable I/O pins.		
A0 - A17	0	I/O	During Master Parallel configuration, these 18 output pins address the configuration EPROM. After configuration, they are user-programmable I/O pins.		
A18 - A21 (XC4003XL to XC4085XL)	ο	I/O	During Master Parallel configuration with an XC4000X master, these 4 output pins add 4 more bits to address the configuration EPROM. After configuration, they are user-pro- grammable I/O pins. (See Master Parallel Configuration section for additional details.)		
D0 - D7	I	I/O	During Master Parallel and Peripheral configuration, these eight input pins receive con- figuration data. After configuration, they are user-programmable I/O pins.		
DIN	I	I/O	During Slave Serial or Master Serial configuration, DIN is the serial configuration data input receiving data on the rising edge of CCLK. During Parallel configuration, DIN is the D0 input. After configuration, DIN is a user-programmable I/O pin.		
DOUT	Ο	I/O	During configuration in any mode but Express mode, DOUT is the serial configuration data output that can drive the DIN of daisy-chained slave FPGAs. DOUT data changes on the falling edge of CCLK, one-and-a-half CCLK periods after it was received at the DIN input. In Express modefor XC4000E and XC4000X only, DOUT is the status output that can drive the CS1 of daisy-chained FPGAs, to enable and disable downstream devices. After configuration, DOUT is a user-programmable I/O pin.		
Unrestricted L	Jser-Prog	rammabl	e I/O Pins		
I/O	Weak Pull-up	I/O	These pins can be configured to be input and/or output after configuration is completed. Before configuration is completed, these pins have an internal high-value pull-up resistor ($25 \text{ k}\Omega - 100 \text{ k}\Omega$) that defines the logic level as High.		

Boundary Scan

The 'bed of nails' has been the traditional method of testing electronic assemblies. This approach has become less appropriate, due to closer pin spacing and more sophisticated assembly methods like surface-mount technology and multi-layer boards. The IEEE Boundary Scan Standard 1149.1 was developed to facilitate board-level testing of electronic assemblies. Design and test engineers can imbed a standard test logic structure in their device to achieve high fault coverage for I/O and internal logic. This structure is easily implemented with a four-pin interface on any boundary scan-compatible IC. IEEE 1149.1-compatible devices may be serial daisy-chained together, connected in parallel, or a combination of the two.

The XC4000 Series implements IEEE 1149.1-compatible BYPASS, PRELOAD/SAMPLE and EXTEST boundary scan instructions. When the boundary scan configuration option is selected, three normal user I/O pins become dedicated inputs for these functions. Another user output pin becomes the dedicated boundary scan output. The details of how to enable this circuitry are covered later in this section.

By exercising these input signals, the user can serially load commands and data into these devices to control the driving of their outputs and to examine their inputs. This method is an improvement over bed-of-nails testing. It avoids the need to over-drive device outputs, and it reduces the user interface to four pins. An optional fifth pin, a reset for the control logic, is described in the standard but is not implemented in Xilinx devices.

The dedicated on-chip logic implementing the IEEE 1149.1 functions includes a 16-state machine, an instruction register and a number of data registers. The functional details can be found in the IEEE 1149.1 specification and are also discussed in the Xilinx application note XAPP 017: "Boundary Scan in XC4000 Devices."

Figure 40 on page 43 shows a simplified block diagram of the XC4000E Input/Output Block with boundary scan implemented. XC4000X boundary scan logic is identical.

Figure 41 on page 44 is a diagram of the XC4000 Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

XC4000 Series devices can also be configured through the boundary scan logic. See "Readback" on page 55.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out and 3-State Control. Non-IOB pins have appropriate partial bit population for In or Out only. PRO-GRAM, CCLK and DONE are not included in the boundary scan register. Each EXTEST CAPTURE-DR state captures all In, Out, and 3-state pins.

The data register also includes the following non-pin bits: TDO.T, and TDO.O, which are always bits 0 and 1 of the

data register, respectively, and BSCANT.UPD, which is always the last bit of the data register. These three boundary scan bits are special-purpose Xilinx test signals.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA provides two additional data registers that can be specified using the BSCAN macro. The FPGA provides two user pins (BSCAN.SEL1 and BSCAN.SEL2) which are the decodes of two user instructions. For these instructions, two corresponding pins (BSCAN.TDO1 and BSCAN.TDO2) allow user scan data to be shifted out on TDO. The data register clock (BSCAN.DRCK) is available for control of test logic which the user may wish to implement with CLBs. The NAND of TCK and RUN-TEST-IDLE is also provided (BSCAN.IDLE).



Figure 40: Block Diagram of XC4000E IOB with Boundary Scan (some details not shown). XC4000X Boundary Scan Logic is Identical.





Figure 41: XC4000 Series Boundary Scan Logic

Instruction Set

The XC4000 Series boundary scan instruction set also includes instructions to configure the device and read back the configuration data. The instruction set is coded as shown in Table 17.

Bit Sequence

The bit sequence within each IOB is: In, Out, 3-State. The input-only M0 and M2 mode pins contribute only the In bit to the boundary scan I/O data register, while the output-only M1 pin contributes all three bits.

The first two bits in the I/O data register are TDO.T and TDO.O, which can be used for the capture of internal signals. The final bit is BSCANT.UPD, which can be used to drive an internal net. These locations are primarily used by Xilinx for internal testing.

From a cavity-up view of the chip (as shown in XDE or Epic), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 42. The device-specific pinout tables for the XC4000 Series include the boundary scan locations for each IOB pin.

BSDL (Boundary Scan Description Language) files for XC4000 Series devices are available on the Xilinx FTP site.

Including Boundary Scan in a Schematic

If boundary scan is only to be used during configuration, no special schematic elements need be included in the schematic or HDL code. In this case, the special boundary scan pins TDI, TMS, TCK and TDO can be used for user functions after configuration.

To indicate that boundary scan remain enabled after configuration, place the BSCAN library symbol and connect the TDI, TMS, TCK and TDO pad symbols to the appropriate pins, as shown in Figure 43.

Even if the boundary scan symbol is used in a schematic, the input pins TMS, TCK, and TDI can still be used as inputs to be routed to internal logic. Care must be taken not to force the chip into an undesired boundary scan state by inadvertently applying boundary scan input patterns to these pins. The simplest way to prevent this is to keep TMS High, and then apply whatever signal is desired to TDI and TCK.



Setting CCLK Frequency

For Master modes, CCLK can be generated in either of two frequencies. In the default slow mode, the frequency ranges from 0.5 MHz to 1.25 MHz for XC4000E and XC4000EX devices and from 0.6 MHz to 1.8 MHz for XC4000XL devices. In fast CCLK mode, the frequency ranges from 4 MHz to 10 MHz for XC4000E/EX devices and from 5 MHz to 15 MHz for XC4000XL devices. The frequency is selected by an option when running the bitstream generation software. If an XC4000 Series Master is driving an XC3000- or XC2000-family slave, slow CCLK mode must be used. In addition, an XC4000XL device driving a XC4000E or XC4000EX should use slow mode. Slow mode is the default.

Data Type	All Other Modes (D0)
Fill Byte	1111111b
Preamble Code	0010b
Length Count	COUNT(23:0)
Fill Bits	1111b
Start Field	Ob
Data Frame	DATA(n-1:0)
CRC or Constant	xxxx (CRC)
Field Check	or 0110b
Extend Write Cycle	—
Postamble	0111111b
Start-Up Bytes	xxh
Legend:	
Not shaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Table 19: XC4000 Series Data Stream Formats

Data Stream Format

The data stream ("bitstream") format is identical for all configuration modes.

The data stream formats are shown in Table 19. Bit-serial data is read from left to right, and byte-parallel data is effectively assembled from this serial bitstream, with the first bit in each byte assigned to D0.

The configuration data stream begins with a string of eight ones, a preamble code, followed by a 24-bit length count and a separator field of ones. This header is followed by the actual configuration data in frames. The length and number of frames depends on the device type (see Table 20 and Table 21). Each frame begins with a start field and ends with an error check. A postamble code is required to signal the end of data for a single device. In all cases, additional start-up bytes of data are required to provide four clocks for the startup sequence at the end of configuration. Long daisy chains require additional startup bytes to shift the last data through the chain. All startup bytes are don't-cares; these bytes are not included in bitstreams created by the Xilinx software.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading and the pulling down of the $\overline{\text{INIT}}$ pin. In Master modes, CCLK and address signals continue to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling Vcc.



Table 22: Pin Functions During Configuration

SLAVE SERIAL <1:1:1>	MASTER SERIAL <0:0:0>	SYNCH. PERIPHERAL <0:1:1>	ASYNCH. PERIPHERAL <1:0:1>	MASTER PARALLEL DOWN <1:1:0>	MASTER PARALLEL UP <1:0:0>	USER OPERATION
M2(HIGH) (I)	M2(LOW) (I)	M2(LOW) (I)	M2(HIGH) (I)	M2(HIGH) (I)	M2(HIGH) (I)	(I)
M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	(0)
M0(HIGH) (I)	M0(LOW) (I)	M0(HIGH) (I)	M0(HIGH) (I)	M0(LOW) (I)	M0(LOW) (I)	(1)
HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	I/O
LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	I/O
ĪNĪT	INIT	INIT	ĪNĪT	INIT	ĪNĪT	I/O
DONE	DONE	DONE	DONE	DONE	DONE	DONE
PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (O)	CCLK (O)	CCLK (O)	CCLK (I)
		RDY/BUSY (O)	RDY/BUSY (O)	RCLK (O)	RCLK (O)	I/O
			RS (I)			I/O
						I/O
		DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	I/O
		DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	I/O
		DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	I/O
		DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	I/O
		DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	I/O
		DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	I/O
		DATA 1 (I)	DATA 1 (I)		DATA 1 (I)	I/O
DIN (I)	DIN (I)					I/O
DOUT	DOUT	DOUT	DOUT	DOUT	DOUT	SGCK4-GCK6-I/O
TDI	TDI	TDI	TDI	TDI	TDI	TDI-I/O
тск	тск	тск	тск	ТСК	тск	TCK-I/O
TMS	TMS	TMS	TMS	TMS	TMS	TMS-I/O
TDO	TDO	TDO	TDO	TDO	TDO	TDO-(O)
	I	1	WS (I)	A0	A0	I/O
				A1	A1	PGCK4-GCK7-I/O
			CS1	A2	A2	I/O
			•	A3	A3	I/O
				A4	A4	I/O
				A5	A5	I/O
				A6	A6	I/O
				A7	A7	I/O
				A8	A8	I/O
				A9	A9	I/O
				A10	A10	I/O
				A11	A11	I/O
				A12	A12	I/O
				A13	A13	I/O
				A14	A14	I/O
				A15	A15	SGCK1-GCK8-I/O
				A16	A16	PGCK1-GCK1-I/O
				A17	A17	I/O
				A18*	A18*	I/O
				A19*	A19*	I/O
				A20*	A20*	I/O
				A21*	A21*	I/O
						ALL OTHERS

The seven configuration modes are discussed in detail in this section. Timing specifications are included.

Slave Serial Mode

In Slave Serial mode, an external signal drives the CCLK input of the FPGA. The serial configuration bitstream must be available at the DIN input of the lead FPGA a short setup time before each rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin.

There is an internal delay of 0.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

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Figure 51 shows a full master/slave system. An XC4000 Series device in Slave Serial mode should be connected as shown in the third device from the left.

Slave Serial mode is selected by a <111> on the mode pins (M2, M1, M0). Slave Serial is the default mode if the mode pins are left unconnected, as they have weak pull-up resistors during configuration.



Figure 51: Master/Slave Serial Mode Circuit Diagram



	Description	5	Symbol	Min	Max	Units
CCLK	DIN setup	1	T _{DCC}	20		ns
	DIN hold	2	T _{CCD}	0		ns
	DIN to DOUT	3	T _{CCO}		30	ns
	High time	4	T _{CCH}	45		ns
	Low time	5	T _{CCL}	45		ns
	Frequency		F _{cc}		10	MHz

Note: Configuration must be delayed until the INIT pins of all daisy-chained FPGAs are High.

Figure 52: Slave Serial Mode Programming Switching Characteristics

Master Serial Mode

In Master Serial mode, the CCLK output of the lead FPGA drives a Xilinx Serial PROM that feeds the FPGA DIN input. Each rising edge of the CCLK output increments the Serial PROM internal address counter. The next data bit is put on the SPROM data output, connected to the FPGA DIN pin. The lead FPGA accepts this data on the subsequent rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal pipeline delay of 1.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

In the bitstream generation software, the user can specify Fast ConfigRate, which, starting several bits into the first frame, increases the CCLK frequency by a factor of eight. For actual timing values please refer to "Configuration Switching Characteristics" on page 68. Be sure that the serial PROM and slaves are fast enough to support this data rate. XC2000, XC3000/A, and XC3100A devices do not support the Fast ConfigRate option.

The SPROM CE input can be driven from either $\overline{\text{LDC}}$ or DONE. Using $\overline{\text{LDC}}$ avoids potential contention on the DIN pin, if this pin is configured as user-I/O, but $\overline{\text{LDC}}$ is then restricted to be a permanently High user output after configuration. Using DONE can also avoid contention on DIN, provided the early DONE option is invoked.

Figure 51 on page 60 shows a full master/slave system. The leftmost device is in Master Serial mode.

Master Serial mode is selected by a <000> on the mode pins (M2, M1, M0).



	Description		Symbol	Min	Max	Units
CCLK	DIN setup	1	T _{DSCK}	20		ns
COLK	DIN hold	2	T _{CKDS}	0		ns

Notes: 1. At power-up, Vcc must rise from 2.0 V to Vcc min in less than 25 ms, otherwise delay configuration by pulling PROGRAM Low until Vcc is valid.

2. Master Serial mode timing is based on testing in slave mode.

Figure 53: Master Serial Mode Programming Switching Characteristics

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	Description		Symbol	Min	Max	Units
	Delay to Address valid	1	T _{RAC}	0	200	ns
RCLK	Data setup time	2	T _{DRC}	60		ns
	Data hold time	3	T _{RCD}	0		ns

Notes: 1. At power-up, Vcc must rise from 2.0 V to Vcc min in less than 25 ms, otherwise delay configuration by pulling PROGRAM Low until Vcc is valid.

2. The first Data byte is loaded and CCLK starts at the end of the first RCLK active cycle (rising edge).

This timing diagram shows that the EPROM requirements are extremely relaxed. EPROM access time can be longer than 500 ns. EPROM data output has no hold-time requirements.

Figure 55: Master Parallel Mode Programming Switching Characteristics